# Single-Shot Shape and Reflectance with Spatial Polarization Multiplexing

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**Abstract**—We propose spatial polarization multiplexing (SPM) for reconstructing object shape and reflectance from a single polarimetric image and demonstrate its application to dynamic surface recovery. Although single-pattern structured light enables single-shot shape reconstruction, the reflectance is challenging to recover due to the lack of angular sampling of incident light and the entanglement of the projected pattern and the surface color texture. We design a spatially multiplexed pattern of polarization that can be robustly and uniquely decoded for shape reconstruction by quantizing the AoLP values. At the same time, our spatial-multiplexing enables single-shot ellipsometry of linear polarization by projecting differently polarized light within a local region, which separates the specular and diffuse reflections for BRDF estimation. We achieve this spatial polarization multiplexing with a constrained de Bruijn sequence. Unlike single-pattern structured light with intensity and color, our polarization pattern is invisible to the naked eye and retains the natural surface appearance which is essential for accurate appearance modeling and also interaction with people. We experimentally validate our method on real data. The results show that our method can recover the shape, the Mueller matrix, and the BRDF from a single-shot polarimetric image. We also demonstrate the application of our method to dynamic surfaces.

Index Terms—Computational Photography, Structured Light, Depth Reconstruction, Reflectance

# **1** INTRODUCTION

S HAPE and reflectance are the foundation of our visual world. Many visual applications require accurate estimates of them. For example, we can use measured shapes to create a replica by 3D printing, import real-world objects into a virtual world, and understand a 3D scene. We can use measured reflectances to render the object under novel lighting conditions and edit the surface material. Acquiring shape and reflectance from captured light is a long-standing research topic in computer vision for which many methods have been proposed.

Structured light and Time-of-Flight (ToF) are active sensing methods for accurate shape acquisition. Structured light [1] uses the duality of a projector and a camera for triangulation. The projector throws the designed spatial light patterns onto the target surface. By decoding the reflected patterns to establish correspondences between the projector and the camera, the surface geometry can be recovered. ToF systems [2] measure the distance of a surface point from the camera as the time the emitted light takes to return to the camera after being reflected by the surface. These methods, however, only offer us the object geometry, not the radiometric property governing its appearance, namely the reflectance.

Image-based reflectance acquisition methods often take a photometric approach in lieu of geometric approaches for shape acquisition. The object appearance is determined by the shading (geometry), the illumination, and the reflectance. To disentangle the reflectance from others, existing methods capture many images under different illumination, assuming a known object shape or by simultaneously recovering the surface normals. Some methods exploit polarimetric reflection that enables the separation of specular and diffuse reflections [3], [4] to avoid the need for dense angular sampling.

By integrating these methods into a single measurement system, recent studies address the simultaneous recovery of shape and reflectance with structured light using an LED array and an LCD mask [5], polarimetric ToF [6], and structured polarization [7]. These methods, however, require many polarimetric images of the scene captured under different projector settings. This fundamentally limits these methods to static scenes. Shape and reflectance acquisition of dynamic scenes can enable a much wider range of applications, for example, a relightable motion capture that can be used to acquire datasets and create synthetic data for computer vision tasks. Another potential application is the analysis of temporal changes in both shape and material, such as phase transition and chemical reaction.

Simultaneous acquisition of object shape and reflectance in a single shot is challenging. Although some shape acquisition methods use only a single image and can be applied to dynamic scenes, reflectance acquisition inherently requires multiple observations under different lighting conditions (*e.g.*, angular sampling or different polarization states of incident light) due to the complex behavior of light reflection on the surface. For simultaneous shape and reflectance acquisition, the single illumination pattern needs to include both the encodings of the ray positions and samplings of the ray directions, and also enable disentanglement of them. Moreover, intensity or color patterns alter the visual appearance of the object which would be visible to human perception. This is often not desirable.

In this paper, we realize single-shot shape and reflectance acquisition by deriving a novel structured polarization method. Structured polarization [7] is a recently

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Results on a deforming surface



Fig. 1. We propose spatial polarization multiplexing, which recovers shape and reflectance with a single shot by using a polarimetric projectorcamera system. We design a spatial polarization multiplexing pattern that simultaneously encodes the incident ray and reconstructs the Mueller matrix of linear polarization. The Mueller matrix allows for separating diffuse and specular reflections that we can use for reflectance reconstruction. Our method enables shape reconstruction and relighting even for dynamic surfaces.

proposed structured light system that uses polarization for encoding and decoding by per-pixel Angle of Linear Polarization (AoLP) control, instead of intensity and color used in classic structured light. Our key idea is to design a novel structured polarization pattern by spatially multiplexing so that it simultaneously encodes the incident ray and samples polarimetric reflections of differently polarized incident light. Since the human visual system cannot perceive polarization, our polarization pattern is invisible and suitable for applications that allow dynamic interactions with people.

Decoding the single polarization pattern is challenging as reflection modulates the polarization state. Although SPI-DeRS [7] projects two uniform patterns whose polarization orientations are perpendicular to each other to extract true AoLP patterns from the modulated patterns, it requires two additional shots. In this paper, to decode a spatial polarization multiplexing pattern from a single polarimetric image, we quantize AoLP values the polarization projector emits. We observe that diffuse reflection on the surface only perturbs the projected AoLP due to its small DoLP. As long as the AoLP modulation is smaller than the width of the quantization, we can decode the projected AoLP pattern.

We can recover the BRDF from only a single polarimetric image through single-shot ellipsometry of linear polarization after the decoding. Ellipsometry, which measures polarimetric behaviors of the reflection on the surface, provides cues for surface properties, such as surface normals and BRDFs [4], [7]. It, however, requires multiple shots captured with varied polarization orientation of incident light. The spatial polarization multiplexing enables us to use neighboring pixels where the differently polarized light is projected for single-shot ellipsometry, instead of changing the polarization orientation at the same pixel.

Based on these ideas, we design a stripe AoLP pattern with quantized AoLP values so that we can uniquely decode it and AoLP values of neighboring stripes are different for ellipsometry of linear polarization. Inspired by an RGB

 TABLE 1

 Comparisons between past methods and our method. Our method

 simultaneously reconstructs object shape and BRDF with only a single

 shot. Additionally, unlike structured light methods using light intensity,

 our method retains natural object appearance by using an invisible

 polarization pattern.

Method	Single shot	BRDF acquisition	Invisible pattern
Single patt. SL	$\checkmark$		
ToF	$\checkmark$		$\checkmark$
pToF [6]		$\checkmark$	$\checkmark$
Unified SL [5]		$\checkmark$	
SPIDeRS [7]		$\checkmark$	$\checkmark$
Ours	$\checkmark$	$\checkmark$	$\checkmark$

single-shot shape recovery method [8], we propose to generate a de Bruijn sequence which is constrained to have different neighboring symbols. By assigning the quantized AoLP values to the symbols of the de Bruijn sequence, we create a spatial polarization multiplexing pattern.

We experimentally validate our method on real data and show that it enables both accurate shape reconstruction and ellipsometry from a single shot. We demonstrate the relighting of real objects with the acquired shape and BRDF from a single polarimetric image. Furthermore, we also apply our method to dynamic objects for shape reconstruction and relighting.

We believe our method provides a foundation of spatiotemporal 3D and material data capture and analysis methods with just a simple projector-camera system.

# 2 RELATED WORK

Table 1 summarizes comparisons between past single-view shape acquisition methods and ours.

# 2.1 Shape Acquisition

Structured light measures an object shape by projecting patterns designed with light intensity or color from a projector and decoding the observed patterns after reflected on the surface. Several patterns have been proposed for different purposes [1]. Multi-pattern structured light, such as Binary codes [9], N-ary codes [10], phase-shifting [11], [12], [13], and Hamiltonian coding [14], enables robust and accurate shape measurement by increasing the number of patterns. These multi-pattern methods cannot reconstruct a moving or deforming object due to an assumption of a static scene during pattern projection.

Single-pattern structured light enables the shape reconstruction of dynamic scenes by capturing continuous frame images and decoding each frame. Fourier transform profilometry methods encode the height from a reference plane as a phase of a sinusoidal pattern and decode it by extracting and unwrapping the phase from the captured image [15], [16], [17]. Pengyu et al. [18] propose Fourier-assisted phase shifting that exploits Fourier transform profilometry to apply phase-shifting to dynamic scenes. Spatially multiplexed patterns use continuous intensity [19] or wavelength [20] gradation and discrete codes represented with colors and geometric features [21]. Some methods use a single grid pattern for robustness to local discontinuities on the surface [22], [23], [24]. Learning-based methods for decoding a single pattern structured light have also been proposed [25], [26], [27].

Other methods propose different encoding and decoding strategies that do not directly use correspondences between a camera and a projector. Furukawa *et al.* [28] exploit motion blur of structured light for depth reconstruction of dynamic scenes, instead of decoding a designed pattern. Recently, Mirdehghan *et al.* [29] propose a robust and dense method for decoding structured light that uses only three or four patterns, TurboSL, by considering the decoding of the patterns as a neural inverse rendering problem.

These methods, however, only focus on shape acquisition, which limits their applications.

#### 2.2 Reflectance Acquisition

Reflectance is represented as a Bidirectional Reflectance Distribution Function (BRDF), a function of incident and outgoing direction. Matusik *et al.* [30] measure BRDFs of 100 materials by capturing a sphere illuminated by a point light source orbiting around it for each material. Light stage and light dome enable dense angular sampling of incident light directions for spatially varying BRDF (SVBRDF) and surface normal acquisition [31]. Some methods [3], [32], [33] exploit specular and diffuse separation with linearly or circularly polarized light to acquire reflectance under spherical or natural illumination. Baek *et al.* [4] use the acquired Mueller matrix of linear polarization to reconstruct reflectance and surface normal.

These methods, however, use multiple images captured under different lighting conditions to decompose the complex reflection on the surface into specular and diffuse reflections. Our method simultaneously acquires shape and reflectance with only a single shot.

# 2.3 Joint Acquisition of Shape and Reflectance

A multi-view and controlled lighting setup is used to acquire shape and reflectance [34], [35], [36], [37], [38], [39]. Recent studies enable simultaneous acquisition of shape and reflectance with a projector-camera system. Baek and Heide [6] use temporal changes in the polarization of reflected light to measure the surface depths, normals, and material parameters. Xu *et al.* [5] propose a unified structured light, which enables spatial sampling for shape reconstruction and angular sampling for BRDF reconstruction with LED arrays and LCD masks, respectively. Ichikawa *et al.* [7] propose a structured polarization that measures a depth map with encoded AoLP patterns and also estimates normals and reflectances with polarimetric reflection. These methods, however, require multiple shots and take a long time for a capture process.

In contrast, our method captures both shape and reflectance from only a single polarimetric image. Our spatial polarization multiplexing simultaneously encodes the projector rays and samples polarimetric reflections. Additionally, as the naked eye cannot perceive the polarization pattern, our method retains the natural appearance of an object during the measurement process, unlike structured light methods. This does not prevent the perception and action of people and enables a wider range of applications.

## **3 P**REREQUISITE

We first review the properties of polarized light [40] and a polarization projector that can modulate per-pixel polarization [7], [41].

#### 3.1 Polarization

Light is a transverse electromagnetic wave and the orientation of its vibration plane varies over time. Light emitted from a natural source randomly changes its oscillating orientation within an extremely short time, referred to as unpolarized light. Polarized light has a periodically rotating vibration plane and is called elliptically polarized light due to its elliptical trajectory of the electromagnetic field. We can represent polarized light as a superposition of linearly and circularly polarized light. While the orientation of linearly polarized light is constant, circularly polarized light rotates its vibration plane at a constant speed. Partially polarized light is between polarized and unpolarized light.

A polarization filter lets through only light with a specific oscillating orientation. Light intensity through the polarization filter of angle  $\phi_c$  is expressed as

$$I(\phi_c) = \overline{I}(1 + \rho_L \cos(2\phi_c - 2\phi_L)), \qquad (1)$$

where  $\overline{I}$  is the average intensity over the filter angle,  $\rho_L$  is the strength of linear polarization, referred to as Degree of Linear Polarization (DoLP), and  $\phi_L$  is the orientation of linear polarization, referred to as Angle of Linear Polarization (AoLP). By mounting the polarization filter in front of a camera and capturing at least three images with different filter angles, we can reconstruct the linear polarization state represented with  $\overline{I}$ ,  $\rho_L$ , and  $\phi_L$ .

The polarimetric camera has on-chip four polarization filters of different angles,  $0^{\circ}$ ,  $45^{\circ}$ ,  $90^{\circ}$ , and  $135^{\circ}$ , for each

 $2 \times 2$  matrix of the sensor array. It enables us to capture linear polarization states with a single shot. The polarimetric camera cannot distinguish unpolarized and circularly polarized light.

Mueller calculus with Stokes vectors is a useful mathematical representation to formulate polarimetric behavior on the surface. Stokes vector represents partially polarized light, defined as

$$\boldsymbol{s} = \begin{bmatrix} s_0 \\ s_1 \\ s_2 \\ s_3 \end{bmatrix} = \begin{bmatrix} I(0) + I(\frac{\pi}{2}) \\ I(0) - I(\frac{\pi}{2}) \\ I(\frac{\pi}{4}) - I(\frac{3}{4}\pi) \\ s_3 \end{bmatrix} = \begin{bmatrix} 2\overline{I}\rho_L \cos(2\phi_L) \\ 2\overline{I}\rho_L \sin(2\phi_L) \\ s_3 \end{bmatrix}, \quad (2)$$

where  $s_0$  represents the light intensity,  $s_1$  and  $s_2$  represent the linearly polarized light, and  $s_3$  represents the circularly polarized light. From Eq. (2), the DoLP and AoLP can be extracted as

$$\rho_L = \frac{\sqrt{s_1^2 + s_2^2}}{s_0}, \quad \phi_L = \frac{1}{2} \tan^{-1} \left(\frac{s_2}{s_1}\right),$$
(3)

respectively. The Mueller matrix represents a change of the polarization state as

$$s^{o} = M s^{i} , \qquad (4)$$

where  $s^i$  and  $s^o$  are Stokes vectors of input and output light, respectively. We use the Mueller calculus to analyze the polarimetric reflection on an object surface.

#### 3.2 Polarization Projector

A polarization projector is designed to control polarization orientation at each pixel, instead of light intensity [7], [41]. The key component of the polarization projector is a Spatial Light Modulator (SLM) made of a Twisted Nematic (TN) liquid crystal.

The liquid crystal shows both fluidity and anisotropy, which allows us to change its anisotropy with the external force. The TN liquid crystal has perpendicularly aligned elongated molecules on each side, resulting in helically oriented molecules through its inside. Such helical structure guides and changes the polarization orientation of incident light. By applying the voltage between both sides of the liquid crystal, we can disturb its helical structure and weaken its guidance of polarization orientation, which enables us to control the rotation of polarization.

The SLM has a two-dimensional array of TN liquid crystals placed between electrodes. By controlling the voltage between the electrodes of each cell, we can rotate the polarization orientation of incident polarized light at each pixel independently and throw the polarization pattern.

## 3.3 Polarimetric Reflection of Polarization Pattern

SPIDeRS [7] uses the polarization projector to measure object shape and BRDF by decoding the AoLP patterns. The thrown AoLP patterns encoding the projector pixels are reflected on the target surface. The polarimetric reflectance model represents modulations of polarization states on the surface as the Mueller matrix [4], [39], [42], [43]. Baek *et* 

*al.* [4] approximate the polarimetric specular reflection by assuming a co-axial setup

$$M^{s} \approx c^{s} \begin{bmatrix} 1 & 0 & 0 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & -1 & 0 \\ 0 & 0 & 0 & -1 \end{bmatrix}.$$
 (5)

where  $c^s$  is a radiometric specular term that represents the shading and specular BRDF. Baek *et al.* [4] also approximate the diffuse reflection

$$M^{d} \approx c^{d} \begin{bmatrix} 1 & m_{01}^{a} & m_{02}^{a} & 0\\ m_{10}^{d} & 0 & 0 & 0\\ m_{20}^{d} & 0 & 0 & 0\\ 0 & 0 & 0 & 0 \end{bmatrix},$$
 (6)

where  $c^d$  is a radiometric diffuse term that represents the shading and diffuse BRDF and  $m_{ij}$  consists of Fresnel transmittance on the surface.

SPIDeRS analyzes these approximated polarimetric reflections to propose a method for decoding the AoLP pattern modulated by polarimetric reflection. SPIDeRS, however, requires two uniform polarization patterns along with encoded polarization patterns for decoding robust to diffuse reflection and BRDF reconstruction. In contrast, we design a novel polarization pattern by spatial-multiplexing that reconstructs shape and BRDF with only a single shot.

# 4 SPATIAL POLARIZATION MULTIPLEXING

Although many patterns for spatial-multiplexing structured light have been proposed [8], [44], [45], these patterns are supposed to be used for encodings with intensity or color and only shape acquisition. In this paper, we design a novel polarization pattern that enables both depth and BRDF reconstruction by fully exploiting polarimetric behavior on the surface.

We use the same projector-camera settings as SPI-DeRS [7]. To balance the co-axial assumption of polarimetric specular reflection for decoding and enough parallax for triangulation, we locate the projector and camera with enough parallax and at a distance from the target object. We also assume no ambient light.

#### 4.1 Overview

Figure 2 shows an our polarization pattern for spatial polarization multiplexing as an AoLP image. We use a stripe pattern of quantized AoLP values. By identifying the location of each stripe on the captured polarimetric image, we obtain disparity between the projector and camera for shape reconstruction. We can also measure Mueller matrices of the surface with a single shot by observing the polarimetric reflections of the differently polarized incident light of the neighboring stripes.

## 4.2 Quantization of AoLPs

We encode and decode structured polarization with AoLP of projected and observed light. From Eqs. (4) to (6), when projecting the polarized light with DoLP  $\rho_L^i$  and AoLP  $\phi_L^i$ , we can express the AoLP of the reflected light  $\phi_L^o$  as

$$\phi_L^o = \frac{1}{2} \tan^{-1} \frac{c^d m_{20}^d - c^s \rho_L^i \sin\left(2\phi_L^i\right)}{c^d m_{10}^d + c^s \rho_L^i \cos\left(2\phi_L^i\right)} \,. \tag{7}$$



Fig. 2. We design a spatial polarization multiplexing pattern with quantized AoLP values. The projector pixels are encoded as indices of the lines. We set different AoLP values in neighboring lines for the unambiguous detection of each line and well-conditioned ellipsometry of linear polarization.

The diffuse reflection terms  $c^d m_{10}^d$  and  $c^d m_{20}^d$  modulate the projected AoLP pattern  $\phi_L^i$ . The past structured polarization method [7] extracts the true AoLP pattern by using additional polarimetric images with uniformly polarized patterns, which enables accurate decoding of continuous sinusoidal patterns. This extraction method, however, requires additional shots and prevents us from realizing single-shot decoding.

To resolve this problem, we quantize AoLP values used for the projection. The quantization makes the detection of projected AoLP from observed AoLP robust to small modulation.

We analyze the effect of diffuse polarization in Eq. (7) by reparameterizing  $m_{10}^d$  and  $m_{20}^d$  with diffuse DoLP and AoLP

$$\rho_L^d = \sqrt{\left(m_{10}^d\right)^2 + \left(m_{20}^d\right)^2}, \quad \phi_L^d = \frac{1}{2} \tan^{-1} \left(\frac{m_{20}^d}{m_{10}^d}\right).$$
(8)

By using  $\rho_L^d$  and  $\phi_L^d$ , we rewrite Eq. (7) as

$$\phi_L^o = \frac{1}{2} \tan^{-1} \frac{c^d \rho_L^d \sin\left(2\phi_L^d\right) - c^s \rho_L^i \sin\left(2\phi_L^i\right)}{c^d \rho_L^d \cos\left(2\phi_L^d\right) + c^s \rho_L^i \cos\left(2\phi_L^i\right)} \,. \tag{9}$$

While the DoLP of polarization projector  $\rho_L^i$  can be approximately set as 1 [7], the DoLP of diffuse reflection is small. Polarization of diffuse reflection is modeled with Fresnel transmission on the surface [4], [43]. In the left of Fig. 3, we plot the DoLP of diffuse reflection modeled as Fresnel transmission for the zenith angle of surface normal when the refractive index is 1.5. The diffuse DoLP  $\rho_L^d$  is much lower than 1.0 for all zenith angles. Especially when the zenith angle is less than 45°, the diffuse DoLP is  $\rho_L^d < 0.05$ .

In the right of Fig. 3, we show AoLP modulation for  $\frac{c^d}{c^s}$  computed from Eq. (9) when  $\frac{\rho_L^d}{\rho_L^i} = 0.05$  and diffuse and specular polarization orientations are orthogonal. Even when the diffuse reflection  $c^d$  is dominant, the AoLP modulation is within only a few degrees. When this AoLP modulation is smaller than the width of AoLP quantization, we can correctly detect the projected AoLP. In our experiments, we validate that we can robustly decode our polarization pattern with quantized AoLPs.

Even though the quantization makes detection of the projected AoLP robust to the AoLP modulation by diffuse

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Fig. 3. Left: DoLP of diffuse reflection modeled as Fresnel transmission for the zenith angle of the surface normal. The DoLP is much lower than 1.0 for most zenith angles. **Right:** AoLP modulation for the ratio of the diffuse reflection  $c^d$  and specular reflection  $c^s$ . Even when the diffuse intensity is dominant, the modulation of incident AoLP is within only a few degrees.



Fig. 4. Concept of our method for single-shot linear polarization ellipsometry. Per-pixel polarization control enables ellipsometry without rotating the polarization filter by using neighboring pixels. We fully exploit the polarimetric behavior represented as the Mueller matrix for BRDF reconstruction with only a single polarimetric image.

reflection, there are two cases where the correct decoding is difficult. First, the object surface shows very narrow specular highlights. In this case,  $c^s = 0$  on most of the surface regions and the reflected AoLP is largely modulated. Second, the zenith angle of the surface normal is close to the grazing angle, which causes large diffuse DoLP  $\rho_L^d$ .

## 4.3 Single-Shot Ellipsometry of Linear Polarization

The Mueller matrix represents how the polarization of incident light affect that of reflected light. To measure the Mueller matrix with polarimetric images, we project differently polarized light and capture polarimetric images under each illumination. When observing Stokes vectors  $s_1^o, s_2^o, \ldots, s_N^o$  under illuminations of Stokes vectors  $s_1^i, s_2^i, \ldots, s_N^i$ , from Eq. (4), the Mueller matrix is obtained as

$$\boldsymbol{M} = \boldsymbol{S}^{o} \boldsymbol{S}^{i\mathrm{T}} \left( \boldsymbol{S}^{i} \boldsymbol{S}^{i\mathrm{T}} \right)^{-1}, \qquad (10)$$

where  $S^i = \begin{bmatrix} s_1^i & s_2^i & \dots & s_N^i \end{bmatrix}$  and  $S^o = \begin{bmatrix} s_1^o & s_2^o & \dots & s_N^o \end{bmatrix}$ . Since the Mueller matrix of linear polarization has 9 components, we need at least three pairs of observed and incident Stokes vectors. The Mueller matrix includes richer information on surface properties, such as reflectance and material, than just a radiometric reflection. Measuring the Mueller matrix, however, requires multiple polarimetric images.

We obtain the Mueller matrix by using a single spatial polarization multiplex pattern. As shown in Fig. 4, we use

neighboring pixels of the polarization projector, which is similar to a polarimetric camera that divides a single pixel into subpixels equipped with polarization filters of different angles. By changing the polarization states of incident light within a local region, we can obtain some sets of observed Stokes vectors and incident Stokes vectors and reconstruct the Mueller matrix of that local region.

Since the discrepancy of points caused by the spatially multiplexed pattern produces noise and artifacts in the Mueller matrix as well as observation noise, we regularize the Mueller matrix by our near co-axial settings. From Eqs. (5) and (6), the Mueller matrix is regularized as

$$m_{23} = 0, \ m_{32} = 0, \ m_{11} = -m_{22},$$
 (11)

where  $m_{ij}$  is the (i, j) element of the Mueller matrix M. Furthermore, we use a transpositional reciprocity relationship of the Mueller matrix [46]. When interchanging the incident light and viewing directions, the Mueller matrices of polarimetric reflection are transposition of each other. As our setup allows for co-axial assumption, we approximate the Mueller matrix as the symmetry matrix. Due to the difference between the z-axis directions of the camera and projector in the polarimetric reflectance model, either the x or y-axis is flipped and we can express the transpositional reciprocity relationship as

$$m_{01} = m_{10}, \ m_{02} = -m_{20}.$$
 (12)

First, we obtain the second and third rows of the Mueller matrix by formulating the linear equation as

where  $s_{i,j}^o$  is the *j*-th element of the  $s_i^o$ . Then, we obtain the first row of the Mueller matrix by formulating the linear equation as

$$\begin{bmatrix} s_{1,0}^{o} \\ \vdots \\ s_{N,0}^{o} \\ m_{10} \\ -m_{20} \end{bmatrix} = \begin{bmatrix} \mathbf{S}^{i\mathrm{T}} \\ 0 & 1 & 0 \\ 0 & 0 & 1 \end{bmatrix} \begin{bmatrix} m_{00} \\ m_{01} \\ m_{02} \end{bmatrix} .$$
(14)

## 4.4 Spatial Polarization Multiplexing Pattern

We design a spatial polarization multiplexing pattern with quantized AoLPs that enables simultaneous shape acquisition and ellipsometry of linear polarization. There are two requirements for this pattern. First, we need to decode it uniquely from an observed polarimetric image for depth reconstruction. Second, three different AoLP values are included within local regions for Mueller matrix acquisition. Existing single-pattern structured light methods exploit a de Bruijn sequence, whose every substring of the de Bruijn sequence is unique, to design a stripe pattern with color and intensity that can be decoded uniquely [8], [45].

We modify the encoding method based on the de Bruijn sequence for our polarization pattern design. We assign each quantized AoLP value to symbols of the sequence. If we use the original de Bruijn sequence, the generated stripe polarization pattern has some pairs of neighboring lines with the same AoLP values, which prevent ellipsometry and unambiguous line detection. To resolve this problem, we generate the constrained de Bruijn sequence whose every set of three sequential elements is different by modifying the generation method of the sequence. The de Bruijn sequence is generated as the Eulerian path of the oriented graph whose nodes represent all possible strings of  $n_{\rm db} - 1$  length and  $k_{db}$  symbols and edges represent the substrings of  $n_{db}$ length [47]. Since we can concatenate one of  $k_{\rm db}$  symbols to the front or backward of each node to make substrings, the in-degree and out-degree of each node are  $k_{db}$ .

We modify the oriented graph by removing the nodes and edges representing the substrings that violate our constraints. When we set  $n_{\rm db} \geq 3$  and  $k_{\rm db} \geq 3$ , we can concatenate one of  $k_{\rm db} - 2$  symbols to the front or backward of each left node. Since the in-degree and out-degree of each node are  $k_{\rm db} - 2$  in the modified graph, it has the Eulerian path. We find the Eulerian path of the modified graph by Hierholzer's algorithm to generate the constrained de Bruijn sequence. We make our polarization pattern by applying the quantized AoLP values to the generated sequence of the symbols.

We detect the lines of the projected stripe pattern in the captured polarimetric image for each scanline, the horizontal line on the image. In the local window on the scanline, each pixel votes the symbols by quantizing the observed AoLP. We select the symbols that gather enough votes and locate the center position of each selected symbol as detected symbols. By sliding the local window, we can find the symbols of the stripe pattern and their positions across the scanline. To mitigate the inaccuracy of the edges of the lines, we mask out the pixel with the large gradient in the Stokes vector image in the local window.

We use dynamic programming to decode the sequence of the detected symbols, following past methods [8], [45]. We define a score function as

$$\operatorname{score}(d_i, p_j) = \cos\left(2\phi_{d_i} - 2\phi_{p_j}\right) - \cos\left(2\phi_{\mathrm{th}}\right) \,, \qquad (15)$$

where  $d_i$  is the symbol of the *i*-th detected line,  $p_j$  is the symbol of the *j*-th line of the projected pattern, and  $\phi_{d_i}$  and  $\phi_{p_j}$  are the AoLP values corresponding the symbols  $d_i$  and  $p_j$ , respectively. We set the threshold of matching as  $\phi_{\text{th}} = 30^\circ$ . Global matching using dynamic programming can handle mislabeling, misdetection, and occlusion.

We reconstruct the 3D points of decoded pixels by triangulation. The decoding also provides a pair of incident and observed Stokes vectors for each point. We use the neighboring matched points on the scanline to obtain Mueller matrices from Eqs. (13) and (14).

#### 4.5 BRDF Estimation

We estimate a BRDF by using the acquired shape and Mueller matrix. As shown in Eqs. (5) and (6), since  $m_{11}$  and

 $m_{\rm 22}$  show only specular reflection, we can separate specular and diffuse reflections as

$$\hat{c}^s = \frac{m_{11} - m_{22}}{2} \ \hat{c}^d = m_{00} - \hat{c}^s \,.$$
 (16)

For each reflection, we optimize a parametric BRDF model by fitting rendered specular and diffuse reflections to obtained reflections in Eq. (16). We adopt Fresnel microfacet BRDF model [43], which describes polarimetric and radiometric surface (specular) and body (diffuse) reflections in the unified model. We compute surface normals of each point of reconstructed point clouds by Principal Component Analysis (PCA) of neighboring points.

For surface reflection, we assume that the material parameters, refractive index  $\mu$ , surface reflection albedo  $k_s$ , and microfacet distribution  $\alpha$  and  $\beta$ , are uniform on the surface. For body reflection, we assume mesoscopic roughness  $\kappa$  is fixed at 0 and body reflection albedo  $K_b$  is spatially varying. First, we optimize the material parameters related to specular reflection

$$\min_{\mu,k_s,\alpha,\beta} \sum_{i}^{N} |\hat{c}_i^s - \bar{c}_i^s| , \qquad (17)$$

where  $\hat{c}_i^s$  and  $\bar{c}_i^s$  are the observed and rendered specular reflections at the *i*-th correspondence and N is the number of correspondences. Then, by using the optimized material parameters, we optimize the body reflection albedos

$$\min_{\boldsymbol{K}_{b}} \sum_{i}^{N} \left| \hat{c}_{i}^{d} - \overline{c}_{i}^{d} \right| \,, \tag{18}$$

where  $\hat{c}_i^d$  and  $\overline{c}_i^d$  are the observed and rendered diffuse reflections at *i*-th correspondences. Since the body reflection albedo  $k_{b,i} \in \mathbf{K}_b$  represents the scale of  $\overline{c}_i^d$ , we can analytically solve Eq. (18).

# **5** EXPERIMENTAL RESULTS

We experimentally validate the effectiveness of our method on real data. Our polarization projector consists of a green LED telecentric illuminator with a polarizer, a spatial light modulator with a resolution of 1024×768 (HOLOEYE LC2012), and convex lenses. We capture polarimetric images with a commercial monochrome polarimetric camera (Lucid TRI050S-PC).

We set the line width of the stripe pattern as 12 pixels on the polarization projector. Since we need 86 lines, we set the substring length  $n_{\rm db}$  and the number of symbols  $k_{\rm db}$  of the constrained de Bruijn sequence as  $n_{\rm db} = 3$  and  $k_{\rm db} = 6$ . In this setting, the sequence length is 122. We quantize the AoLP values at even intervals from 0° to 80°.

Since the reconstructed points are not dense on the image, we linearly interpolate depths, Mueller matrices, and optimized body reflection albedos on each scanline for visualization.

## 5.1 Shape Accuracy

Figure 5 shows depth reconstruction results on real objects with different colors and materials: plaster, cloth and leather. We obtain the ground truth shapes by structured light with Gray code and phase shifting patterns. Our method can

Ground Truth Captured image



Ours

Fig. 5. Shape reconstruction results of real-world objects with different textures and shapes. The numbers below each depth map indicate the mean and median of depth errors in millimeters. Our method can reconstruct object shapes robustly to surface textures and materials. Additionally, since the polarization pattern has little effect on light intensity, our method can retain a natural object appearance.

reconstruct the object shapes from only a single polarimetric image robustly to surface materials and colors by designing the spatial polarization multiplexing pattern with quantized AoLPs and decoding it by global matching. The numbers below each depth map indicate the mean and median of depth errors. Considering that the depth error average and standard deviation of Intel Realsense L515 [48] is < 5 mmand 2.5 mm at 1m distance, respectively, the accuracy of our method is comparable with it. Additionally, unlike standard structured light, our polarization pattern does not change object appearance, which enables a wider range of applications. Large errors and artifacts at the object contour are caused by the difficulties in global matching in that region.

#### 5.2 Ellipsometry Accuracy

Figure 6 shows that our method achieves linear polarization ellipsometry, which requires multiple polarimetric images, from only a single polarimetric image. We obtain the ground truth Mueller matrix by capturing 26 polarimetric images under differently polarized light. In (2,1) and (3,1) elements, the Mueller matrix acquired by our method can capture the normal-dependent diffuse polarization as seen in the ground truth. In (1,1) and (2,2) elements, our method also captures the polarimetric specular reflection that retains the polarization state of incident light.

We observe strong artifacts in  $m_{01}$  and  $m_{02}$ . Due to the large ratio of  $m_{00}$  to  $m_{01}$  and  $m_{02}$ , shading differences between spatially multiplexed incident light dominantly affect  $m_{01}$  and  $m_{02}$ . We will be able to mitigate this effect by improving the resolution of the polarization pattern.

Figure 7 shows the results of the specular and diffuse decomposition. Since our method exploits polarimetric reflections of differently polarized light with a single shot, we can successfully separate surface colors and specular highlights. We can use the decomposition result and measured object shape for BRDF estimation and relighting.



Fig. 6. Mueller matrix measured by our method with a single polarimetric image. We realize linear polarization ellipsometry from even a single polarimetric image while an existing system using a projector with a polarization filter and polarimetric camera requires multiple captures. Our method can capture the normal-dependent diffuse polarization in (2,1) and (3,1) elements and polarimetric specular reflection in (2,2) and(3,3) elements. As shown in Fig. 5, we simultaneously capture the object shape.



Fig. 7. Decomposition results of specular and diffuse reflections. Our method enables us to estimate each reflection component from a single polarimetric image by exploiting the polarimetric behavior of specular and diffuse reflections. We can use the separation results for BRDF estimation and relighting.

# 5.3 Relighting

Figure 8 shows relighting results by using reconstructed shape and estimated BRDF. To remove points with inaccurate depth at the object contours, we mask out the regions where the zenith angle of the surface normal computed by PCA is larger than 60°. Specular and diffuse separation using Mueller matrix enables BRDF estimation from a single polarimetric image. The relighting results show plausible surface color texture and specular highlight rendering under novel lighting conditions.

## 5.4 Dynamic Surface

We apply our method to a dynamic surface by capturing continuous frames and using each frame. Figure 1 shows the shape reconstruction and relighting results of a swelling rubber balloon at some frames. As the balloon swells, the specular highlight becomes narrow and strong due to changes in the surface roughness of the stretched surface. While reconstructing the deforming shape, our method can capture such BRDF changes and relight the dynamic deformable surface at each frame.



Fig. 8. Relighting results using acquired shape and BRDF. The spheres at the top right indicate the direction of light as Lambertian shading. We can successfully relight real-world objects with only a single shot by fully exploiting the polarimetric reflection of the spatially multiplexed polarized light.

# 6 CONCLUSION

We propose spatial polarization multiplexing that simultaneously reconstructs shape and reflectance with only a single shot. Our polarization pattern design that uses the quantized AoLPs and the constrained de Bruijn sequence enables both unique decoding and Mueller matrix measurement. We use the obtained Mueller matrix to separate specular and diffuse reflections and reconstruct BRDF by combining the separated reflections and the reconstructed shape. Our experimental results on the real data show that we can decode the polarization pattern robustly to surface reflectance and reconstruct the object shapes, Mueller matrices, and reflectances from only a single polarimetric image. We also demonstrate that we can apply our method to dynamic surfaces.

Due to a single spatial light modulator, we control a polarization state of only a single wavelength and estimate monochrome reflectance. Since the polarization states can be different for each wavelength, we can extend our method from monochrome reflectance to RGB reflectance in the future. Furthermore, encoding with multiple wavelengths will enable more flexible pattern design and detailed depth reconstruction while keeping the pattern invisible.

#### ACKNOWLEDGMENTS

This work was in part supported by JSPS KAKENHI 20H05951, 21H04893, 23K28110, 24H00742, 23KJ1367; JST JPMJAP2305; and RIKEN GRP.

#### REFERENCES

- J. Salvi, S. Fernandez, T. Pribanic, and X. Llado, "A state of the art in structured light patterns for surface profilometry," *PR*, vol. 43, no. 8, pp. 2666–2680, 2010. 1, 3
- R. Lange and P. Seitz, "Solid-State Time-of-Flight Range Camera," IEEE Journal of quantum electronics, vol. 37, no. 3, pp. 390–397, 2001.
- [3] W.-C. Ma, T. Hawkins, P. Peers, C.-F. Chabert, M. Weiss, and P. E. Debevec, "Rapid Acquisition of Specular and Diffuse Normal Maps from Polarized Spherical Gradient Illumination." in *Proceedings of the 18th Eurographics Conference on Rendering Techniques*, 2007, pp. 183–194. 1, 3
- [4] Seung-Hwan Baek, Daniel S. Jeon, Xin Tong, and Min H. Kim, "Simultaneous Acquisition of Polarimetric SVBRDF and Normals," ACM TOG, vol. 37, pp. 1 – 15, 2018. 1, 2, 3, 4, 5
- [5] X. Xu, Y. Lin, H. Zhou, C. Zeng, Y. Yu, K. Zhou, and H. Wu, "A unified spatial-angular structured light for single-view acquisition of shape and reflectance," in *CVPR*, 2023, pp. 206–215. 1, 2, 3
- [6] S.-H. Baek and F. Heide, "All-photon Polarimetric Time-of-Flight Imaging," in CVPR, 2022, pp. 17876–17885. 1, 2, 3
- [7] T. Ichikawa, S. Nobuhara, and K. Nishino, "SPIDeRS: Structured Polarization for Invisible Depth and Reflectance Sensing," in *CVPR*, 2024, pp. 25 077–25 085. 1, 2, 3, 4, 5
- [8] Zhang, Li and Curless, Brian and Seitz, Steven M, "Rapid Shape Acquisition Using Color Structured Light and Multi-pass Dynamic Programming," in *3DPVT*. IEEE, 2002, pp. 24–36. 2, 4, 6
  [9] J. L. Posdamer and M. D. Altschuler, "Surface Measurement by
- [9] J. L. Posdamer and M. D. Altschuler, "Surface Measurement by Space-encoded Projected Beam Systems," *Computer Graphics and Image Processing*, vol. 18, no. 1, pp. 1–17, 1982. 3
- [10] D. Časpi, N. Kiryati, and J. Shamir, "Range Imaging with Adaptive Color Structured Light," *IEEE TPAMI*, vol. 20, no. 5, pp. 470–480, 1998. 3
- [11] V. Srinivasan, H.-C. Liu, and M. Halioua, "Automated phasemeasuring profilometry: a phase mapping approach," *Applied Optics*, vol. 24, no. 2, pp. 185–188, 1985. 3
- [12] M. Gupta and S. K. Nayar, "Micro Phase Shifting," in CVPR. IEEE, 2012, pp. 813–820. 3
- [13] D. Moreno, K. Son, and G. Taubin, "Embedded Phase Shifting: Robust Phase Shifting with Embedded Signals," in CVPR, 2015, pp. 2301–2309. 3
- [14] M. Gupta and N. Nakhate, "A Geometric Perspective on Structured Light Coding," in ECCV, 2018, pp. 87–102. 3
- [15] Takeda, Mitsuo and Mutoh, Kazuhiro, "Fourier Transform Profilometry for the Automatic Measurement of 3-D Object Shapes," *Applied Optics*, vol. 22, no. 24, pp. 3977–3982, 1983. 3
- [16] X. Su and Q. Zhang, "Dynamic 3-D shape measurement method: A review," Optics and Lasers in Engineering, vol. 48, no. 2, pp. 191– 204, 2010. 3
- [17] Yang, Lili and Li, Fu and Xiong, Zhiwei and Shi, Guangming and Niu, Yi and Li, Ruodai, "Single-shot Dense Depth Sensing with Frequency-division Multiplexing Fringe Projection," *Journal* of Visual Communication and Image Representation, vol. 46, pp. 139– 149, 2017. 3
- [18] Cong, Pengyu and Xiong, Zhiwei and Zhang, Yueyi and Zhao, Shenghui and Wu, Feng, "Accurate Dynamic 3D Sensing with Fourier-assisted Phase Shifting," *IEEE Journal of Selected Topics in Signal Processing*, vol. 9, no. 3, pp. 396–408, 2014. 3
  [19] B. Carrihill and R. Hummel, "Experiments with the Intensity Ratio
- [19] B. Carrihill and R. Hummel, "Experiments with the Intensity Ratio Depth Sensor," *Computer Vision, Graphics, and Image Processing*, vol. 32, no. 3, pp. 337–358, 1985. 3
- [20] J. Tajima and M. Iwakawa, "3-D data acquisition by Rainbow Range Finder," in *ICPR*, vol. 1. IEEE, 1990, pp. 309–313. 3
- [21] X. Zhou, C. Zhou, Y. Kang, T. Zhang, and X. Mou, "Pattern Encoding of Robust M-Array Driven by Texture Constraints," *IEEE Transactions on Instrumentation and Measurement*, vol. 72, pp. 1–16, 2023. 3

- [22] Kawasaki, Hiroshi and Furukawa, Ryo and Sagawa, Ryusuke and Yagi, Yasushi, "Dynamic Scene Shape Reconstruction Using a Single Structured Light Pattern," in CVPR. Ieee, 2008, pp. 1–8.
- [23] Sagawa, Ryusuke and Ota, Yuichi and Yagi, Yasushi and Furukawa, Ryo and Asada, Naoki and Kawasaki, Hiroshi, "Dense 3D Reconstruction Method Using a Single Pattern for Fast Moving Object," in *ICCV*. IEEE, 2009, pp. 1779–1786. 3
- [24] Sagawa, Ryusuke and Kawasaki, Hiroshi and Kiyota, Shota and Furukawa, Ryo, "Dense One-shot 3D Reconstruction by Detecting Continuous Regions with Parallel Line Projection," in *ICCV*. IEEE, 2011, pp. 1911–1918. 3
- [25] A.-H. Nguyen, B. Sun, C. Q. Li, and Z. Wang, "Different structured-light patterns in single-shot 2D-to-3D image conversion using deep learning," *Applied Optics*, vol. 61, no. 34, pp. 10105– 10115, 2022. 3
- [26] Y. Li, J. Peng, Y. Zhang, and Z. Xiong, "Self-Distilled Depth From Single-Shot Structured Light With Intensity Reconstruction," *IEEE Transactions on Computational Imaging*, vol. 9, pp. 678–691, 2023. 3
- [27] J. Song, K. Liu, A. Sowmya, and C. Sun, "Super-Resolution Phase Retrieval Network for Single-Pattern Structured Light 3D Imaging," *IEEE TIP*, vol. 32, pp. 537–549, 2022. 3
- [28] Furukawa, Ryo and Sagawa, Ryusuke and Kawasaki, Hiroshi, "Depth Estimation Using Structured Light Flow–Analysis of Projected Pattern Flow on an Object's Surface," in *ICCV*, 2017, pp. 4640–4648. 3
- [29] P. Mirdehghan, M. Wu, W. Chen, D. B. Lindell, and K. N. Kutulakos, "TurboSL: Dense Accurate and Fast 3D by Neural Inverse Structured Light," in CVPR, 2024, pp. 25067–25076. 3
- [30] W. Matusik, H. Pfister, M. Brand, and L. McMillan, "A Data-Driven Reflectance Model," ACM TOG, vol. 22, no. 3, pp. 759–769, Jul. 2003. 3
- [31] Nam, Giljoo and Lee, Joo Ho and Wu, Hongzhi and Gutierrez, Diego and Kim, Min H, "Simultaneous Acquisition of Microscale Reflectance and Normals," ACM TOG, vol. 35, no. 6, pp. 185–1, 2016. 3
- [32] Ghosh, Abhijeet and Chen, Tongbo and Peers, Pieter and Wilson, Cyrus A and Debevec, Paul, "Circularly Polarized Spherical Illumination Reflectometry," in ACM TOG, 2010, pp. 1–12. 3
- [33] Riviere, Jérémy and Reshetouski, Ilya and Filipi, Luka and Ghosh, Abhijeet, "Polarization Imaging Reflectometry in the Wild," ACM TOG, vol. 36, no. 6, pp. 1–14, 2017. 3
- [34] Z. Zhou, Z. Wu, and P. Tan, "Multi-view Photometric Stereo with Spatially Varying Isotropic Materials," in CVPR, 2013, pp. 1482– 1489. 3
- [35] B. Tunwattanapong, G. Fyffe, P. Graham, J. Busch, X. Yu, A. Ghosh, and P. Debevec, "Acquiring Reflectance and Shape from Continuous Spherical Harmonic Illumination," ACM TOG, vol. 32, no. 4, pp. 1–12, 2013. 3
- [36] K. Kang, C. Xie, C. He, M. Yi, M. Gu, Z. Chen, K. Zhou, and H. Wu, "Learning Efficient Illumination Multiplexing for Joint Capture of Reflectance and Shape." ACM TOG, vol. 38, no. 6, pp. 165–1, 2019.
- [37] M. Holroyd, J. Lawrence, and T. Zickler, "A Coaxial Optical Scanner for Synchronous Acquisition of 3D Geometry and Surface Reflectance," ACM TOG, vol. 29, no. 4, pp. 1–12, 2010. 3
- [38] G. Nam, J. H. Lee, D. Gutierrez, and M. H. Kim, "Practical SVBRDF Acquisition of 3D Objects with Unstructured Flash Photography," ACM TOG, vol. 37, no. 6, pp. 1–12, 2018. 3
- [39] I. Hwang, D. S. Jeon, A. Muñoz, D. Gutierrez, X. Tong, and M. H. Kim, "Sparse Ellipsometry: Portable Acquisition of Polarimetric SVBRDF and Shape with Unstructured Flash Photography," ACM TOG, vol. 41, no. 4, pp. 1–14, 2022. 3, 4
- [40] Eugene Hecht, *Optics*, 5th ed. Pearson, 2016. 3
- [41] Z. Li, Z. Zhong, S. Nobuhara, K. Nishino, and Y. Zheng, "Fooling Polarization-based Vision using Locally Controllable Polarizing Projection," in CVPR, 2024, pp. 24706–24715. 3, 4
- [42] Y. Kondo, T. Ono, L. Sun, Y. Hirasawa, and J. Murayama, "Accurate Polarimetric BRDF for Real Polarization Scene Rendering," in *ECCV*. Springer, 2020, pp. 220–236. 4
- [43] T. Ichikawa, Y. Fukao, S. Nobuhara, and K. Nishino, "Fresnel Microfacet BRDF: Unification of Polari-Radiometric Surface-Body Reflection," in CVPR, 2023, pp. 16489–16497. 4, 5, 7
- [44] Boyer, Kim L and Kak, Avinash C, "Color-encoded Structured Light for Rapid Active Ranging," IEEE TPAMI, no. 1, pp. 14–28, 1987. 4

- [45] Pages, Jordi and Salvi, Joaquim and Collewet, Christophe and Forest, Josep, "Optimised De Bruijn Patterns for One-shot Shape Acquisition," *Image and Vision Computing*, vol. 23, no. 8, pp. 707– 720, 2005. 4, 6
- [46] Y. Ding, Y. Ji, Z. Chen, M. Zhou, S. B. Kang, and J. Ye, "Polarimetric Helmholtz Stereopsis," *IEEE TPAMI*, vol. 46, no. 07, pp. 4597–4611, Jul. 2024. 6
- [47] Fredricksen, Harold, "A Survey of Full Length Nonlinear Shift Register Cycle Algorithms," *SIAM review*, vol. 24, no. 2, pp. 195– 221, 1982. 6
- [48] Intel, "LiDAR Camera L515 ; Intel® RealSense™ Depth and Tracking Cameras," https://www.intelrealsense.com/lidar-camera-l515/, accessed: 8 April 2025. 7